


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,120	SUN, SHANG-PIN	
	Examiner	Art Unit	
	Nathan Danielsen	2627	

SEARCHED			
Class	Subclass	Date	Examiner
369	53.22	3/29/2006	ND
369	53.23	3/29/2006	ND

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search in class 369, subclasses 53.22 and 53.23	3/29/2006	ND
Consulted Thang Tran for art	3/29/2006	ND
Search through discrimination references compiled by Jorge Ortiz-Criado	3/30/2006	ND